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Deep Learning-Based Object Detection/Classification

Guest Editor:

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Message from the Guest Editor

Dear Colleagues,

Object detection and classification are two important tasks in computer vision, and their algorithm, architecture, system and application scope are very wide. Here are some common application scenarios:

- 1. Algorithm: Object detection and classification algorithms are used to identify and classify objects in images or videos.
- 2. Architecture: Object detection and classification architecture mainly refers to the computer system used to process images or videos.
- 3. System: Object detection and classification systems can be applied to many fields. For example, human–computer interaction systems can detect and classify human actions and other behaviors in images or videos; autonomous driving systems can detect and classify the objects in the road.
- Application: Object detection and classification applications are very extensive, including but not limited to human-computer interaction, security monitoring, manufacturing and other fields.

In short, object detection and classification have broad application prospects in many fields of computer vision technology, which can help people better understand the visual world.











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Message from the Editor-in-Chief

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